

SN74ACT573-Q1 Automotive Octal D-Type Transparent Latches With 3-State Outputs

1 Features

- Operation of 4.5V to 5.5V V_{CC}
- Inputs accept voltages to 5.5V
- Maximum t_{pd} of 9.5ns at 5V
- Inputs are TTL-voltage compatible

2 Applications

- Parallel data storage
- Digital bus buffer

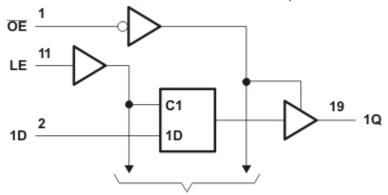
3 Description

These 8-bit latches feature 3-state outputs designed specifically for driving highly capacitive or relatively low-impedance loads. The devices are particularly suitable for implementing buffer registers, I/O ports, bus drivers, and working registers.

Package Information

PART NUMBER PACKAGE ⁽¹⁾		PACKAGE SIZE(2)	BODY SIZE(3)
	DGS (VSSOP, 20)	5.1mm x 4.9mm	5.1mm x 3mm
SN74ACT573-Q1	PW (TSSOP, 20)	6.5mm × 6.4mm	6.50mm x 4.40mm
	RKS (WQFN, 20)	4.5mm × 2.5mm	4.5mm × 2.5mm

- For more information, see Section 11.
- The package size (length × width) is a nominal value and includes pins, where applicable.
- The body size (length × width) is a nominal value and does not include pins.



To Seven Other Channels

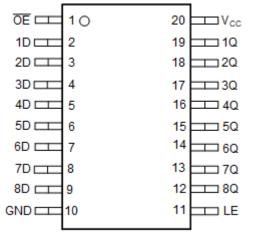
Logic Diagram (Positive Logic)



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4 Pin Configuration and Functions



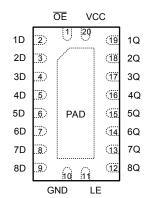


Figure 4-2. SN74ACT573-Q1 RKS Package, 20-Pin VQFN (Top View)

Figure 4-1. SN74ACT573-Q1 DGS or PW Package, 20-Pin VSSOP or TSSOP (Top View)

Table 4-1. Pin Functions

	PIN	TYPE ⁽¹⁾	DESCRIPTION
NAME	NO.	ITPE	DESCRIPTION
ŌĒ	1	ı	Output enable, active low
1D	2	ı	1D input
2D	3	I	2D input
3D	4	ı	3D input
4D	5	ı	4D input
5D	6	ı	5D input
6D	7	ı	6D input
7D	8	I	7D input
8D	9	ı	8D input
GND	10	G	Ground
LE	11	I	Latch enable input
8Q	12	0	8Q output
7Q	13	0	7Q output
6Q	14	0	6Q output
5Q	15	0	5Q output
4Q	16	0	4Q output
3Q	17	0	3Q output
2Q	18	0	2Q output
1Q	19	0	1Q output
V _{CC}	20	Р	Positive supply
Thermal	Pad ⁽²⁾	_	The thermal pad can be connected to GND or left floating. Do not connect to any other signal or supply.

⁽¹⁾ I = Input, O = Output, I/O = Input or Output, G = Ground, P = Power.

⁽²⁾ For RKS package only.



5 Specifications

5.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted)(1)

			MIN	MAX	UNIT
V _{CC}	Supply voltage range		-0.5	7	V
VI	Input voltage range ⁽²⁾		-0.5	V _{CC} + 0.5 V	V
Vo	Output voltage range ⁽²⁾		-0.5	V _{CC} + 0.5 V	V
I _{IK}	Input clamp current	V _I < -0.5 V or V _I > V _{CC} + 0.5 V	-	±20	mA
I _{OK}	Output clamp current	V _O < -0.5 V or V _O > V _{CC} + 0.5 V	-	±50	mA
Io	Continuous output current	$V_O = 0$ to V_{CC}		±50	mA
	Continuous output current through V _{CC} or GND			±200	mA
TJ	Junction temperature			150	°C
T _{stg}	Storage temperature		-65	150	°C

⁽¹⁾ Operation outside the *Absolute Maximum Ratings* may cause permanent device damage. Absolute maximum ratings do not imply functional operation of the device at these or any other conditions beyond those listed under *Recommended Operating Conditions*. If briefly operating outside the *Recommended Operating Conditions* but within the *Absolute Maximum Ratings*, the device may not sustain damage, but it may not be fully functional. Operating the device in this manner may affect device reliability, functionality, performance, and shorten the device lifetime.

5.2 ESD Ratings

			VALUE	UNIT
Electrostatic	Human body model (HBM), per AEC Q100-002 HBM ESD Classification Level 2 ⁽¹⁾	±2000		
V _(ESD)		Charged device model (CDM), per AEC Q100-011 CDM ESD Classification Level C4B	±1000	V

⁽¹⁾ AEC Q100-002 indicate that HBM stressing shall be in accordance with the ANSI/ESDA/JEDEC JS-001 specification.

5.3 Recommended Operating Conditions

over operating free-air temperature range (unless otherwise noted)

Spec	Description	Condition	MIN	MAX	UNIT
V _{CC}	Supply voltage		4.5	5.5	V
V _{IH}	High-level input voltage		2		V
V _{IL}	Low-Level input voltage	Low-Level input voltage			V
VI	Input Voltage	Input Voltage			V
Vo	Output Voltage	Output Voltage			V
I _{OH}	High-level output current			-24	mA
I _{OL}	Low-level output current	Low-level output current			mA
Δt/Δν	Input transition rise or fall rate		20	ns/V	
T _A	Operating free-air temperature	Operating free-air temperature			°C

5.4 Thermal Information

	THERMAL METRIC ⁽¹⁾	DGS (VSSOP)	PW (TSSOP)	RKS (VQFN)	UNIT
THERMAL METRIC		20 PINS	20 PINS	20 PINS	UNII
$R_{\theta JA}$	Junction-to-ambient thermal resistance	123.6	126.2	67.7	°C/W
R _{0JC(top)}	Junction-to-case (top) thermal resistance	62.2	68.7	72.4	°C/W
$R_{\theta JB}$	Junction-to-board thermal resistance	78.7	77.3	40.4	°C/W
Ψ_{JT}	Junction-to-top characterization parameter	7.8	22.3	10.3	°C/W

Product Folder Links: SN74ACT573-Q1

⁽²⁾ The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

5.4 Thermal Information (continued)

THERMAL METRIC(1)		DGS (VSSOP)	PW (TSSOP)	RKS (VQFN)	UNIT
	THERWAL WETRIC	20 PINS	20 PINS	20 PINS	UNII
Ψ_{JB}	Junction-to-board characterization parameter	78.0	76.9	40.4	°C/W
R _{0JC(bot)}	Junction-to-case (bottom) thermal resistance	N/A	N/A	24.1	°C/W

⁽¹⁾ For more information about traditional and new thermal metrics, see the Semiconductor and IC Package Thermal Metrics application report.

5.5 Electrical Characteristics

over operating free-air temperature range (unless otherwise noted); typical values measured at T_A = 25 °C

PARAMETER	TEST CONDITIONS	V	-40°C	to 125°C		UNIT
PARAMETER	TEST CONDITIONS	V _{cc}	MIN	TYP	MAX	UNII
	I - FOA	4.5 V	4.4	4.49		
	I _{OH} = -50 μA	5.5 V	5.4	5.49		
V	I _{OH} = -24 mA	4.5 V	3.9	4.2		V
V _{OH}	I _{OH} = -24 mA	5.5 V	5	5.2		V
	I _{OH} = -50 mA	5.5 V	4.5	4.9		
	I _{OH} = -75 mA	5.5 V	4	4.6		
	Ι _{ΟΗ} = 50 μΑ	4.5 V		0.01	0.1	
	ΙΟΗ – 30 μΑ	5.5 V		0.01	0.1	
V	I _{OH} = 24 mA	4.5 V		0.2	0.4	V
V _{OL}	I _{OH} = 24 mA	5.5 V		0.2	0.3	V
	I _{OH} = 50 mA	5.5 V		0.3	0.6	
	I _{OH} = 75 mA	5.5 V		0.5	0.9	
I _I	V _I = 5.5 V or GND	0 V to 5.5 V			±1	μA
I _{OZ}	V _O = V _{CC} or GND	5.5 V			±5	μA
I _{CC}	$V_I = V_{CC}$ or GND, $I_O = 0$	5.5 V			80	μA
ΔI _{CC}	VI = VCC – 2.1 V; Any Input	4.5 V to 5.5 V		0.6	1.5	mA
C _I	V _I = V _{CC} or GND	5 V		8		pF
Co	V _O = V _{CC} or GND	5 V		14		pF
C _{PD}	F = 1MHz	5 V		59		pF

5.6 Timing Characteristics

over recommended operating free-air temperature range (unless otherwise noted)

PARAME TER	DESCRIPTION	DESCRIPTION CONDITION		T _A = 25°C		-40°C to 125°C		UNIT
	DESCRIPTION	CONDITION	V _{cc}	MIN	MAX	MIN	MAX	CIVIT
t _W	Pulse duration	LE high	5 V	3.5		4		ns
t _{SU}	Setup time	Data before LE↓	5 V	3		3.5		ns
t _H	Hold time	Data after LE↓	5 V	0		0		ns

5.7 Switching Characteristics

 C_L = 50 pF; over operating free-air temperature range; typical values measured at T_A = 25°C (unless otherwise noted). See *Parameter Measurement Information*

PARAME TER	EDOM (INDUT)	TO (OUTPUT)	LOAD	V	-40°C	C to 125°	С	UNIT
	FROM (INPUT)	TO (OUTPUT) CAPACITANO	CAPACITANCE	V _{CC}	MIN	TYP	MAX	UNII
t _{PLH}	D	Q	C _L = 50pF	5 V		5.2	9.4	ns
t _{PHL}	D	Q	C _L = 50pF	5 V		6.2	10.6	ns

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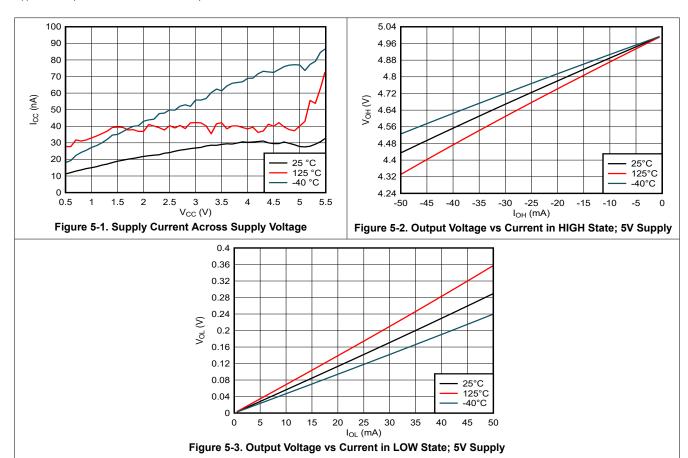


 C_L = 50 pF; over operating free-air temperature range; typical values measured at T_A = 25°C (unless otherwise noted). See *Parameter Measurement Information*

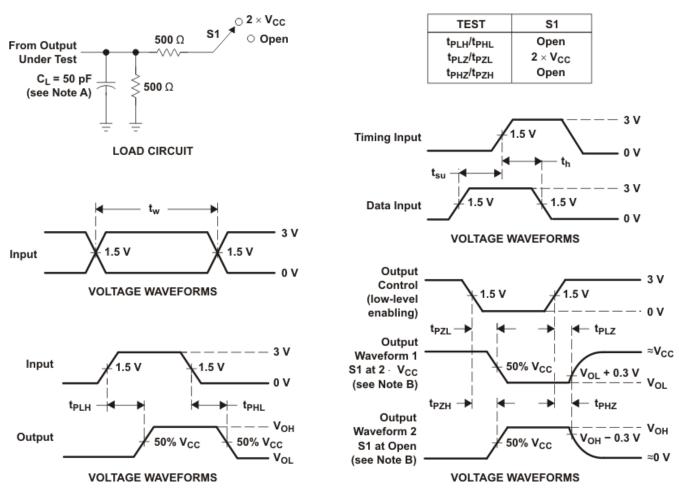
PARAME	FROM (INPUT)	TO (OUTPUT)	LOAD	V	-40°0	c to 125°	С	UNIT
TER	FROW (INFOT)	10 (001701)	CAPACITANCE	V _{cc}	MIN	TYP	MAX	ONII
t _{PLH}	LE	Q	C _L = 50pF	5 V		6.2	9.8	ns
t _{PHL}	LE	Q	C _L = 50pF	5 V		6.3	9.9	ns
t _{PZH}	ŌĒ	Q	C _L = 50pF	5 V		6.1	9.5	ns
t _{PZL}	ŌĒ	Q	C _L = 50pF	5 V		6.3	10	ns
t _{PHZ}	ŌĒ	Q	C _L = 50pF	5 V		5.5	8.2	ns
t _{PLZ}	ŌĒ	Q	C _L = 50pF	5 V		4	6.1	ns

5.8 Typical Characteristics

T_A = 25°C (unless otherwise noted)



6 Parameter Measurement Information



- A. C_L includes probe and jig capacitance.
- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR ≤ 1 MHz, Z_O = 50 Ω, t_r ≤ 2.5 ns, t_f ≤ 2.5 ns.
- D. The outputs are measured one at a time with one input transition per measurement.

Figure 6-1. Load Circuit and Voltage Waveforms

7 Detailed Description

7.1 Overview

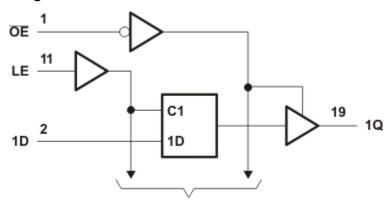
The eight latches are D-type transparent latches. When the latch-enable (LE) input is high, the Q outputs follow the data (D) inputs. When LE is taken low, the Q outputs are latched at the logic levels set up at the D inputs.

A buffered output-enable (\overline{OE}) input can be used to place the eight outputs in either a normal logic state (high or low logic levels) or the high-impedance state. In the high-impedance state, the outputs neither load nor drive the bus lines significantly. The high-impedance state and increased drive provide the capability to drive bus lines in a bus-organized system without need for interface or pullup components.

 $\overline{\text{OE}}$ does not affect the internal operations of the latches. Old data can be retained or new data can be entered while the outputs are in the high-impedance state.

To put the device in the high-impedance state during power up or power down, tie \overline{OE} to V_{CC} through a pullup resistor; the current-sinking capability of the driver determines the minimum value of the resistor.

7.2 Functional Block Diagram



To Seven Other Channels

Figure 7-1. Logic Diagram (Positive Logic)

7.3 Device Functional Modes

Function Table (Each Latch)

	INPUTS		OUTPUT
ŌĒ	LE	D	Q
L	Н	Н	Н
L	Н	L	L
L	L	Χ	Q_0
Н	X	Х	Z

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8 Application and Implementation

Note

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes, as well as validating and testing their design implementation to confirm system functionality.

8.1 Application Information

The SN74ACT573-Q1 can be used to drive signals over relatively long traces or transmission lines. A series damping resistor placed in series with the transmitter's output can be used to reduce ringing caused by impedance mismatches between the driver, transmission line, and receiver. The figure in the *Application Curve* section shows the received signal with three separate resistor values. Just a small amount of resistance can make a significant impact on signal integrity in this type of application.

8.2 Typical Application

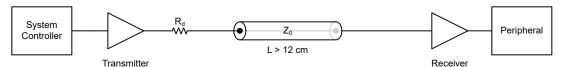


Figure 8-1. Typical Application Block Diagram

8.3 Design Requirements

8.3.1 Power Considerations

Ensure the desired supply voltage is within the range specified in the *Recommended Operating Conditions*. The supply voltage sets the device's electrical characteristics of the device as described in the *Electrical Characteristics* section.

The positive voltage supply must be capable of sourcing current equal to the total current to be sourced by all outputs of the SN74ACT573-Q1 plus the maximum static supply current, I_{CC} , listed in the *Electrical Characteristics*, and any transient current required for switching. The logic device can only source as much current that is provided by the positive supply source. Ensure the maximum total current through V_{CC} listed in the *Absolute Maximum Ratings* is not exceeded.

The ground must be capable of sinking current equal to the total current to be sunk by all outputs of the SN74ACT573-Q1 plus the maximum supply current, I_{CC}, listed in the *Electrical Characteristics*, and any transient current required for switching. The logic device can only sink as much current that can be sunk into its ground connection. Ensure the maximum total current through GND listed in the *Absolute Maximum Ratings* is not exceeded.

The SN74ACT573-Q1 can drive a load with a total capacitance less than or equal to 50pF while still meeting all of the data sheet specifications. Larger capacitive loads can be applied; however, it is not recommended to exceed 50pF.

The SN74ACT573-Q1 can drive a load with total resistance described by $R_L \ge V_O$ / I_O , with the output voltage and current defined in the *Electrical Characteristics* table with V_{OH} and V_{OL} . When outputting in the HIGH state, the output voltage in the equation is defined as the difference between the measured output voltage and the supply voltage at the V_{CC} pin.

Total power consumption can be calculated using the information provided in *CMOS Power Consumption and Cpd Calculation*.

Thermal increase can be calculated using the information provided in *Thermal Characteristics of Standard Linear* and Logic (SLL) Packages and Devices.

CAUTION

The maximum junction temperature, $T_{J(max)}$ listed in the *Absolute Maximum Ratings*, is an additional limitation to prevent damage to the device. Do not violate any values listed in the *Absolute Maximum Ratings*. These limits are provided to prevent damage to the device.

Product Folder Links: SN74ACT573-Q1

8.3.2 Input Considerations

Input signals must cross $V_{IL(max)}$ to be considered a logic LOW, and $V_{IH(min)}$ to be considered a logic HIGH. Do not exceed the maximum input voltage range found in the *Absolute Maximum Ratings*.

Unused inputs must be terminated to either V_{CC} or ground. The unused inputs can be directly terminated if the input is completely unused, or they can be connected with a pull-up or pull-down resistor if the input will be used sometimes, but not always. A pull-up resistor is used for a default state of HIGH, and a pull-down resistor is used for a default state of LOW. The drive current of the controller, leakage current into the SN74ACT573-Q1 (as specified in the *Electrical Characteristics*), and the desired input transition rate limits the resistor size. A $10k\Omega$ resistor value is often used due to these factors.

The SN74ACT573-Q1 has CMOS inputs and thus requires fast input transitions to operate correctly, as defined in the *Recommended Operating Conditions* table. Slow input transitions can cause oscillations, additional power consumption, and reduction in device reliability.

Refer to the *Feature Description* section for additional information regarding the inputs for this device.

8.3.3 Output Considerations

The positive supply voltage is used to produce the output HIGH voltage. Drawing current from the output will decrease the output voltage as specified by the V_{OH} specification in the *Electrical Characteristics*. The ground voltage is used to produce the output LOW voltage. Sinking current into the output will increase the output voltage as specified by the V_{OL} specification in the *Electrical Characteristics*.

Push-pull outputs that could be in opposite states, even for a very short time period, should never be connected directly together. This can cause excessive current and damage to the device.

Two channels within the same device with the same input signals can be connected in parallel for additional output drive strength.

Unused outputs can be left floating. Do not connect outputs directly to V_{CC} or ground.

Refer to the Feature Description section for additional information regarding the outputs for this device.

8.4 Detailed Design Procedure

- Add a decoupling capacitor from V_{CC} to GND. The capacitor needs to be placed physically close to the device and electrically close to both the V_{CC} and GND pins. An example layout is shown in the *Layout* section.
- 2. Ensure the capacitive load at the output is ≤ 50pF. This is not a hard limit; by design, however, it will optimize performance. This can be accomplished by providing short, appropriately sized traces from the SN74ACT573-Q1 to one or more of the receiving devices.
- 3. Ensure the resistive load at the output is larger than $(V_{CC} / I_{O(max)})\Omega$. Doing this will prevent the maximum output current from the *Absolute Maximum Ratings* from being violated. Most CMOS inputs have a resistive load measured in M Ω ; much larger than the minimum calculated previously.
- 4. Thermal issues are rarely a concern for logic gates; the power consumption and thermal increase, however, can be calculated using the steps provided in the application report, *CMOS Power Consumption and Cpd Calculation*.

8.5 Application Curve

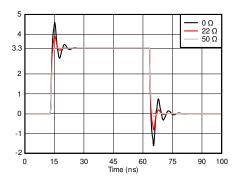


Figure 8-2. Simulated Signal Integrity at the Receiver with Different Damping Resistor (R_d) Values

8.6 Power Supply Recommendations

The power supply can be any voltage between the minimum and maximum supply voltage rating located in the *Recommended Operating Conditions*. Each V_{CC} terminal should have a good bypass capacitor to prevent power disturbance. A $0.1\mu F$ capacitor is recommended for this device. It is acceptable to parallel multiple bypass capacitors to reject different frequencies of noise. The $0.1\mu F$ and $1\mu F$ capacitors are commonly used in parallel. The bypass capacitor should be installed as close to the power terminal as possible for best results.

8.7 Layout

8.7.1 Layout Guidelines

When using multiple-input and multiple-channel logic devices, inputs must never be left floating. In many cases, functions or parts of functions of digital logic devices are unused; for example, when only two inputs of a triple-input AND gate are used or only 3 of the 4 buffer gates are used. Such unused input pins must not be left unconnected because the undefined voltages at the outside connections result in undefined operational states. All unused inputs of digital logic devices must be connected to a logic high or logic low voltage, as defined by the input voltage specifications, to prevent them from floating. The logic level that must be applied to any particular unused input depends on the function of the device. Generally, the inputs are tied to GND or V_{CC} , whichever makes more sense for the logic function or is more convenient.

Product Folder Links: SN74ACT573-Q1



8.7.2 Layout Example

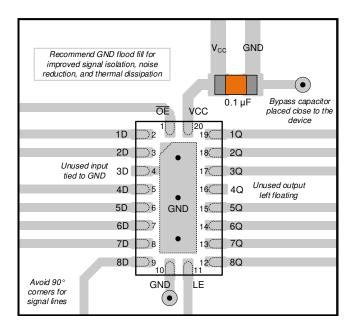


Figure 8-3. Example Layout for the SN74ACT573-Q1 in the RKS Package

9 Device and Documentation Support

9.1 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. Click on *Notifications* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

9.2 Support Resources

TI E2E[™] support forums are an engineer's go-to source for fast, verified answers and design help — straight from the experts. Search existing answers or ask your own question to get the quick design help you need.

Linked content is provided "AS IS" by the respective contributors. They do not constitute TI specifications and do not necessarily reflect TI's views; see TI's Terms of Use.

9.3 Trademarks

TI E2E™ is a trademark of Texas Instruments.

All trademarks are the property of their respective owners.

9.4 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

9.5 Glossary

TI Glossary

This glossary lists and explains terms, acronyms, and definitions.

10 Revision History

Changes from Revision A (March 2024) to Revision B (December 2024) Added DGS package to Package Information table, Pin Configuration and Functions section and Thermal Information table. Changes from Revision * (November 2023) to Revision A (March 2024) Added PW package to Package Information table, Pin Configuration and Functions section and Thermal Information table.

11 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

Product Folder Links: SN74ACT573-Q1

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PACKAGING INFORMATION

Orderable part number	Status	Material type	Package Pins	Package qty Carrier	RoHS	Lead finish/	MSL rating/	Op temp (°C)	Part marking
	(1)	(2)			(3)	Ball material	Peak reflow		(6)
						(4)	(5)		
SN74ACT573QDGSRQ1	Active	Production	VSSOP (DGS) 20	5000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	1M573Q
SN74ACT573QDGSRQ1.A	Active	Production	VSSOP (DGS) 20	5000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	1M573Q
SN74ACT573QPWRQ1	Active	Production	TSSOP (PW) 20	3000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	ACT573Q
SN74ACT573QPWRQ1.A	Active	Production	TSSOP (PW) 20	3000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	ACT573Q
SN74ACT573QWRKSRQ1	Active	Production	VQFN (RKS) 20	3000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	ACT573Q
SN74ACT573QWRKSRQ1.A	Active	Production	VQFN (RKS) 20	3000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	ACT573Q

⁽¹⁾ Status: For more details on status, see our product life cycle.

Multiple part markings will be inside parentheses. Only one part marking contained in parentheses and separated by a "~" will appear on a part. If a line is indented then it is a continuation of the previous line and the two combined represent the entire part marking for that device.

Important Information and Disclaimer: The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

⁽²⁾ Material type: When designated, preproduction parts are prototypes/experimental devices, and are not yet approved or released for full production. Testing and final process, including without limitation quality assurance, reliability performance testing, and/or process qualification, may not yet be complete, and this item is subject to further changes or possible discontinuation. If available for ordering, purchases will be subject to an additional waiver at checkout, and are intended for early internal evaluation purposes only. These items are sold without warranties of any kind.

⁽³⁾ RoHS values: Yes, No, RoHS Exempt. See the TI RoHS Statement for additional information and value definition.

⁽⁴⁾ Lead finish/Ball material: Parts may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

⁽⁵⁾ MSL rating/Peak reflow: The moisture sensitivity level ratings and peak solder (reflow) temperatures. In the event that a part has multiple moisture sensitivity ratings, only the lowest level per JEDEC standards is shown. Refer to the shipping label for the actual reflow temperature that will be used to mount the part to the printed circuit board.

⁽⁶⁾ Part marking: There may be an additional marking, which relates to the logo, the lot trace code information, or the environmental category of the part.

PACKAGE OPTION ADDENDUM

www.ti.com 23-May-2025

OTHER QUALIFIED VERSIONS OF SN74ACT573-Q1:

Catalog: SN74ACT573

Military: SN54ACT573

NOTE: Qualified Version Definitions:

• Catalog - TI's standard catalog product

• Military - QML certified for Military and Defense Applications

PACKAGE MATERIALS INFORMATION

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TAPE AND REEL INFORMATION





A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
SN74ACT573QDGSRQ1	VSSOP	DGS	20	5000	330.0	16.4	5.4	5.4	1.45	8.0	16.0	Q1
SN74ACT573QPWRQ1	TSSOP	PW	20	3000	330.0	16.4	6.95	7.0	1.4	8.0	16.0	Q1
SN74ACT573QWRKSRQ1	VQFN	RKS	20	3000	180.0	12.4	2.8	4.8	1.2	4.0	12.0	Q1



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*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
SN74ACT573QDGSRQ1	VSSOP	DGS	20	5000	353.0	353.0	32.0
SN74ACT573QPWRQ1	TSSOP	PW	20	3000	353.0	353.0	32.0
SN74ACT573QWRKSRQ1	VQFN	RKS	20	3000	210.0	185.0	35.0





NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

 2. This drawing is subject to change without notice.

 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm per side.
- 5. Reference JEDEC registration MO-153.





NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



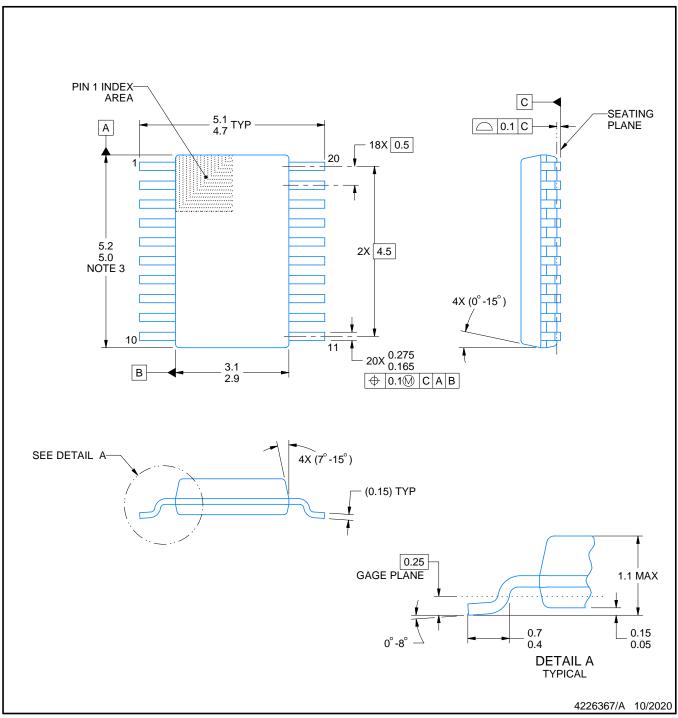


NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.







NOTES:

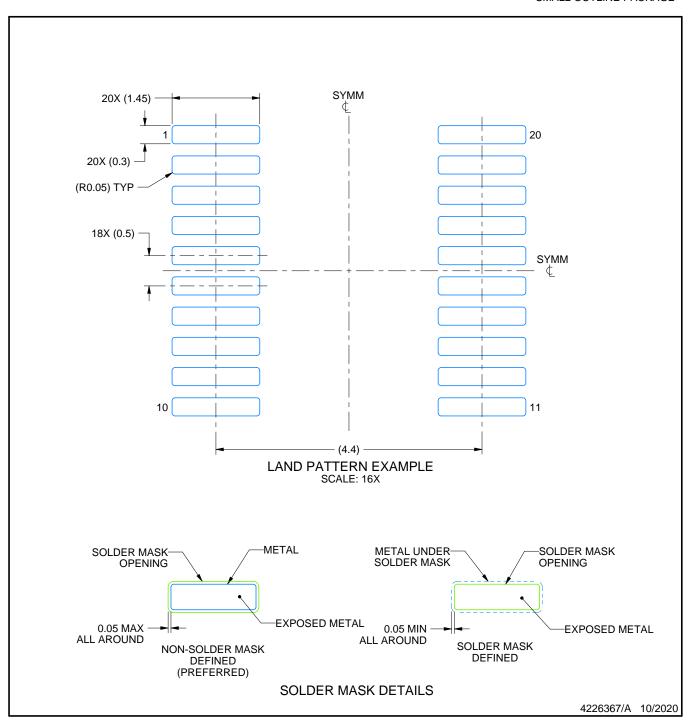
PowerPAD is a trademark of Texas Instruments.

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

 2. This drawing is subject to change without notice.

 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. No JEDEC registration as of September 2020.
- 5. Features may differ or may not be present.

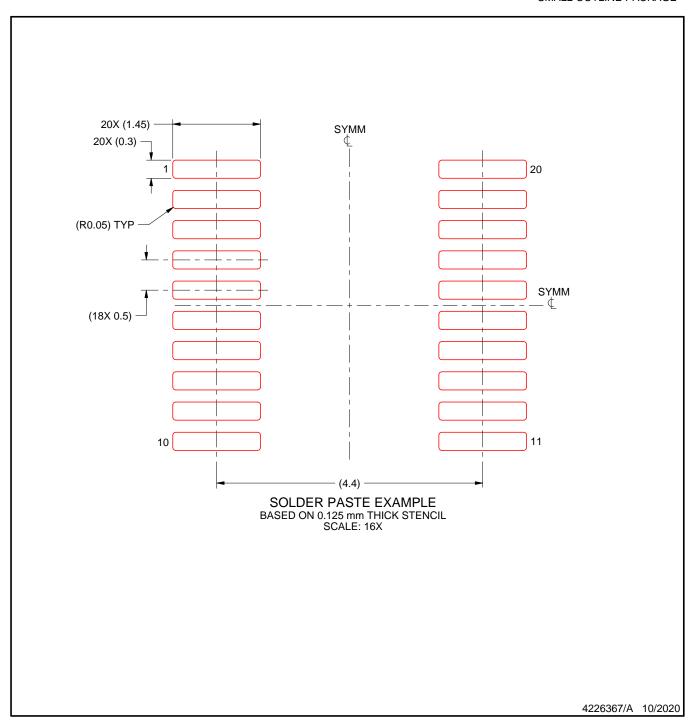




NOTES: (continued)

- 6. Publication IPC-7351 may have alternate designs.
- 7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.
- 8. This package is designed to be soldered to a thermal pad on the board. For more information, see Texas Instruments literature numbers SLMA002 (www.ti.com/lit/slma002) and SLMA004 (www.ti.com/lit/slma004).
- 9. Size of metal pad may vary due to creepage requirement.
- Vias are optional depending on application, refer to device data sheet. It is recommended that vias under paste be filled, plugged or tented.





NOTES: (continued)

- 11. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 12. Board assembly site may have different recommendations for stencil design.



2.5 x 4.5, 0.5 mm pitch

PLASTIC QUAD FLATPACK - NO LEAD

This image is a representation of the package family, actual package may vary. Refer to the product data sheet for package details.



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